

<b>LIST OF ART CITED BY APPLICANT</b>  (PTO-1449)					ATTY. DOCKET NO. <b>DPO-0010</b>		APPLN. SERIAL NO. <b>10/714,926</b>	
					APPLICANT(S) <b>Hae Pyoung LEE</b>			
					FILING DATE <b>November 18, 2003</b>		GROUP <b>2109 2175</b>	
<b>U.S. PATENT DOCUMENTS</b>								
EXAMINER'S INITIALS	*PATENT NO.	*ISSUE DATE	*INVENTOR NAME	CLASS	SUBCLASS	FILING DATE		
<del> </del>								
<b>U.S. PATENT APPLICATION PUBLICATIONS</b>								
	*PATENT APPLN. PUB. NO.	*PUB. DATE	*APPLICANT	CLASS	SUBCLASS			
<del> </del>								
<b>U.S. PATENT APPLICATIONS</b>								
	*APPLN. NO.	*FILING DATE	*INVENTOR	CLASS	SUBCLASS			
<del> </del>								
<b>FOREIGN PATENT DOCUMENTS</b>								
EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation		
						Yes	No	
/A.T./	JP 2001-156930	06/08/2001	JAPAN (full Japanese text and English Abstract)			X		
<b>OTHER ART (Including Author, Title, Date, Pertinent Pages, Publisher, Place of Publication, Etc.)</b>								
/A.T./	Japanese Office Action dated November 10, 2008 (and English language translation)							
<del> </del>								
EXAMINER				DATE CONSIDERED				
/Andrew Tank/				07/30/2009				

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

ALL REFERENCES CONSIDERED EXCEPT WHERE LINED THROUGH. /A.T./